

<b>Notice of References Cited</b>	Application/Control No. 10/565,722		Applicant(s)/Patent Under Reexamination BIJ DE VAATE ET AL.	
	Examiner Dieu Hien T. Duong		Art Unit 2821	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,518,932	02-2003	Matsui et al.	343/770
*	B	US-7,057,563	06-2006	Cox et al.	343/700MS
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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